

Qualification test report 501-78294 Rev. A 15th Feb 2011

1. Introduction

- 1.1 Testing was performed on the LGA2011 Socket to determine if it meets the requirements of product specification 108-78750.
- 1.2 Scope

This report covers the electrical, mechanical and environmental performance requirements of the LGA2011 Socket.

1.3 Conclusion

This test report confirmed that Tyco LGA2011 Socket satisfied the requirements of the product specification of 108-78750.

1.4 Test samples

Samples were taken randomly from production. The following samples were used :

Part Number	Description
1554653-X	LGA2011 Socket Assy

Fig. 1



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2. Test Contents

No.	Test Items	Requirements	Judgement
2.1	Examination of product	Visual Inspection	Acceptable
		No physical damage	
	1	1	
		Electrical Requirements	
2.2	Termination resistance (Low level)	Maximum chain resistance (2~14pos. chain average) : Refer to table1 *1	Acceptable
2.3	Dielectric withstanding	360Vrms, 1 minute	Acceptable
	voltage	Current leakage : 0.5mA Max.	
2.4	Insulation resistance	Impressed voltage 500 VDC.	Acceptable
		$800M\Omega$ Min.	
		Mechanical Requirements	
2.5	Vibration (Random)	Test Package mated Socket by compressive load from	Acceptable
	(Harrasin)	heat sink.	710000100
		Vibration frequency: 10 to 2000Hz (Random)	
		Accelerated velocity: 30.38 m/s ² (3.1 G),rms,	
		Vibration direction: In each of 3 mutually perpendicular	
		planes	
		Maximum chain resistance (2~14pos. chain average)	
		: Refer to table1 (Final)*1	



2.6	Physical shock	EIA-364-27	Acceptable
		Test Package mated Socket by compressive load from	
		heat sink	
		Accelerated velocity: 490 m/s ² (50 G)	
		Waveform: Halfsine	
		Duration: 11 m sec.	
		Number of drops: 3 drops each to normal and reversed	
		directions of X, Y and Z axes, totally 18 drops.	
		Maximum chain resistance (2~14pos. chain average)	
		: Refer to table1 (Final)*1	
			Г
2.7	Durability (Repeated	Operation speed:8 cycle/min.	Acceptable
	mating / unmating)	No. of cycles: 30 cycles	
		Maximum chain resistance (2~14pos. chain average)	
		: Refer to table1 *1	

		Environmental Requirements	
2.8	Thermal humidity	Test package mated Socket with compressive load from heat sink. 85 ℃, 85 % R.H. 1000 hour Maximum chain resistance (2~14pos. chain average) : Refer to table1 *1	Acceptable
2.9	Temperature life (Heat aging)	Test package mated Socket with compressive load from heat sink. 125 °C, Duration: 1000 hours Maximum chain resistance (2~14pos. chain average) : Refer to table1 *1	Acceptable
2.10	Thermal cycling	Test package mated Socket with compressive load from heat sink -25 ℃ / 15 min., +100 ℃ / 15 min. (1cycle) No. of cycle: 1000 cycles. Maximum chain resistance (2~14pos. chain average) : Refer to table1 *1	Acceptable

Fig.2 (continue)

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2.11	Resistance to reflow	Test Socket on PCB.	Acceptable
	soldering heat	(Lead Free, Sn-Ag-Cu solder ball)	
		Solder ball part	
		Pre-Heat 150~170 ℃: 90 sec Min.	
		Heat 225 ℃ min. : 60 ~90sec	
		Heat Peak : 245±5 ℃	
		Other than solder ball : 260 ℃ Max.	
		No physical damage.	

^{*1} Bulk resistances of test CPU are subtracted.

Fig. 2 (end)

Table1: Max Chain Average Resistance

Number of contacts per chain	Max Chain LLCR (mΩ)
2	59.5
4	40.75
6	34.5
8	31.4
10	29.5
12	28.25
14	27.4

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2. Test sequence

Test examination		Test Group									
/ Test sequence	1	2	3	4	5	6	7				
Test sequence (a)											
Examination of product	1,7	1,5	1,5	1,4	1,5	1,4	1,5				
Termination resistance (Low Level)	2,4,6	2,4	2,4		2,4		2,4				
Dielectric withstanding voltage				2							
Insulation resistance				3							
Vibration (Low frequency)	5										
Physical shock	3										
Durability (Repeated ate/unmating)			3 (b)								
Temperature humidity		3(c)									
Temperature life (Heat aging)					3(c)						
Thermal cycling							3(d)				
Solder ball shear force						2					
Resistance to reflow soldering heat						3					

Fig.3

NOTE

- (a) Numbers indicate sequence in which the tests are performed.
- (b) Durability 30X
- (c) Perform termination resistance every 250 hours (until 1000 hours).
- (d) Perform termination resistance every 250 cycles (until 1000 cycles)



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4. Test result

0 ""	Measure				Res	sults		5	
Conditions	Item	n	Unit	MAX.	MIN.	AVE.	SIG.	Requirement	Judgement

Test Group 1 (physical shock & Vibration)										
Initial	Termination	9 Sockets	mΩ	16.88	10.33	13.21	0.79	Refer to table1	Acceptable	
After physical shock	resistance	(1755 chains *2	mΩ	15.36	10.01	12.86	0.78	Refer to table1	Acceptable	
After vibration		2	mΩ	15.81	10.53	12.55	0.73	Refer to table1	Acceptable	

Test Group 2 (Temperature humidity)											
Initial			mΩ	17.32	10.04	12.14	0.82	Refer to table1	Acceptable		
Temp. humidity 250H	Termination	10 Sockets	mΩ	19.19	10.08	11.60	0.77	Refer to table1	Acceptable		
Temp. humidity 500H	resistance	chains)	mΩ	18.22	10.26	11.55	0.75	Refer to table1	Acceptable		
Temp. humidity 750H		*2	mΩ	21.98	10.01	11.51	0.75	Refer to table1	Acceptable		
Temp. humidity 1000H			mΩ	17.59	10.04	11.46	0.69	Refer to table1	Acceptable		



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Conditions	Item	n	Unit	MAX.	MIN.	AVE.	SIG.	Requirement	Judgement

Test Group 3 (Durability)											
Initial		10	mΩ	19.58	11.12	13.52	1.18	Refer to table1	Acceptable		
Durability 5th	Termination resistance	Sockets (1950	mΩ	19.21	10.10	13.14	1.06	Refer to table1	Acceptable		
Durability 10th		chains *2	mΩ	18.54	8.24	13.14	1.14	Refer to table1	Acceptable		
Durability 30th			mΩ	22.60	7.39	13.26	1.15	Refer to table1	Acceptable		

Test Group 4 (Dielectric withstand voltage, Insulation resistance)											
Initial	Dielectric Withstand voltage	24 points		No abnormalities	No abnormalities	Acceptable					
	Insulation resistance	nsulation 24 O Over 800 M	Over 800 M Ω .	800 MΩ Min.	Acceptable						
After thermal	Dielectric Withstand voltage	24 points		No abnormalities	No abnormalities	Acceptable					
cycling	Insulation resistance	24 points	Ω	Over 800 M Ω .	800 MΩ Min.	Acceptable					
After temp.	Dielectric Withstand voltage	24 points		No abnormalities	No abnormalities	Acceptable					
humidity	Insulation resistance	24 points	Ω	Over 800 M Ω .	800 MΩ Min.	Acceptable					



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Conditions	Item	n	Unit	MAX.	MIN.	AVE.	SIG.	Requirement	Judgement

	Test Group 5 (Temperature life)													
Initial			mΩ	20.22	10.24	13.01	1.03	Refer to table1	Acceptable					
Temperature life 250H	Termination Resistance	10 Sockets (1950 chains *2	mΩ	19.76	10.17	12.71	1.16	Refer to table1	Acceptable					
Temperature life 500H			mΩ	20.58	10.17	12.74	1.14	Refer to table1	Acceptable					
Temperature life 750H			mΩ	20.39	10.30	12.74	1.18	Refer to table1	Acceptable					
Temperature life 1000H			mΩ	21.52	10.04	12.70	1.24	Refer to table1	Acceptable					

Test Group6 (Solder ball shear force)											
Initial	Solder ball shear force (Lead free solder ball)	16 contacts x 3 Sockets	gf	926.16	735.42	831.41	40.88	600gf Min	Acceptable		

Test Group6 (Resistance to reflow soldering heat)											
Resistance to reflow soldering heat	Visual observation by magnify scope	10 Sockets	-	No housing damage, irregularity	No irregularity	Acceptable					



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Conditions	Item	n	Unit	MAX.	MIN.	AVE.	SIG.	Requirement	Judgement

	Test Group 7 (Thermal cycling)													
Initial				16.46	10.26	12.44	0.95	Refer to table1	Acceptable					
Thermal cycling 250cycle		1 (1950		15.57	10.52	11.92	0.68	Refer to table1	Acceptable					
Thermal cycling 500cycle	Termination Resistance		mΩ	18.44	10.05	11.70	0.64	Refer to table1	Acceptable					
Thermal cycling 750cycle				14.57	10.41	11.61	0.56	Refer to table1	Acceptable					
Thermal cycling 1000cycle				14.99	10.08	11.51	0.58	Refer to table1	Acceptable					

^{*2} One daisy chain includes 2~14 contacts electrically connected together by the CPU package.



REV	REV. RECORD	PREPA	RED	СНЕ	ECK	APPROVAL		
А	RELEASED	S.AIHARA	9 th Feb '11	Y.SEKIBA	9 th Feb '11	I.ENOMOTO	15 th Feb '11	